PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Nobuaki TAKAZAWA et al.

Application No.: New U.S. Patent Application

Filed: February 27, 2004 Docket No.: 118845

For: METHOD OF PRODUCTION, METHOD OF INSPECTION, AND METHOD OF USE OF

SCANNING PROBE MICROSCOPE PROBE

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the reference listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the reference be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- 1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.
- 2. Relevance of the non-English language reference is discussed in the present specification. (Ref. 1)
- 3. An English-language Abstract of the non-English language reference is attached hereto. (Ref. 1)
- 4. A computer-generated English translation of the following Japanese Patent Publication has been obtained from the website of the Japanese Patent Office ([http://www.jpo.go.jp]), and is attached, but has not been reviewed for accuracy. See Reference 1.

Respectfully submitted,

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JAO:JSA/amo

Date: February 27, 2004

OLIFF & BERRIDGE, PLC P.O. Box 19928 Alexandria, Virginia 22320 Telephone: (703) 836-6400 DEPOSIT ACCOUNT USE AUTHORIZATION Please grant any extension necessary for entry; Charge any fee due to our Deposit Account No. 15-0461

Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE	ATTY 118845	DOCKET NO.		APPLICATION NO. New U.S. Patent Application		
INFORMATION DISCLOSURE STATEMENT								
(Use several sheets if necessary)				APPLICANTS Nobuaki TAKAZAWA et al.				
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)								
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EXAMINER	*.			,	DATE CONSIDERE	D		
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

Date: February 27, 2004